TOSHIBA CMOS DIGITAL INTEGRATED CIRCUIT SILICON MONOLITHIC

TC74HC652AP

OCTAL BUS TRANSCEIVER / REGISTER (3-STATE)

The TC74HC652A is high speed CMOS OCTAL BUS TRANSCEIVER/REGISTER fabricated with silicon gate CMOS technology.

It achieves the high speed operation similar to equivalent LSTTL while maintaining the CMOS low power dissipation. This device is bus transceiver with 3-state outputs, D-type flip-flops, and control circuitry arranged for multiplexed transmission of data directly from the internal registers.

When the enable input GAB and GBA are held high, the A1 thru A8 become inputs and the B1 thru B8 become outputs. When the GAB and $\overline{\text{GBA}}$ are held low, the A1 thru A8 become output and the B1 thru B8 become inputs. When GAB is low and \overline{GBA} is high, the outputs functions of the A and B Busses are disabled.

The select inputs (SAB, SBA) can multiplex stort and realtime (transparent mode) data.

Data on the A Bus or B Bus can be clocked into the registers on the positive going transition of either CAB or CBA clock inputs, respectively.

All inputs are equipped with protection circuits against static discharge or transient excess voltage.

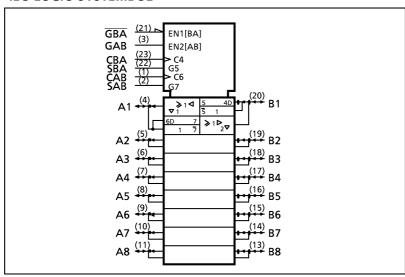
FEATURES:

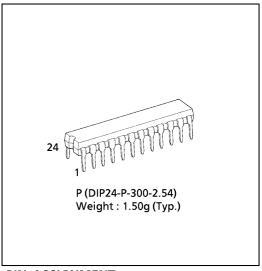
- at $V_{CC} = 5V$

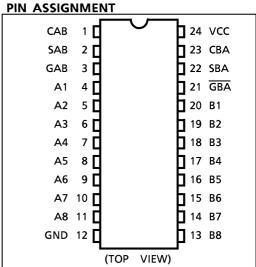
- Output Drive Capability 15 LSTL Loads
 Symmetrical Output Impedance 16 LSTL Loads
 Symmetrical Output Impedance 16 LSTL Loads
 Balanced Propagation Delays 16 LSTL Loads
 Wide Operating Voltage Range VCC (opr.) = 2V~6V

- Pin and Function Compatible with 74LS652

IEC LOGIC SYSTEMBOL







APPLICATION NOTES

- 1) Do not apply a signal to any bus terminal when it is in the output mode. Damage may result.
- 2) All floating (high impedance) bus terminals must have their input levels fixed by means of pull up or pull down resistors.

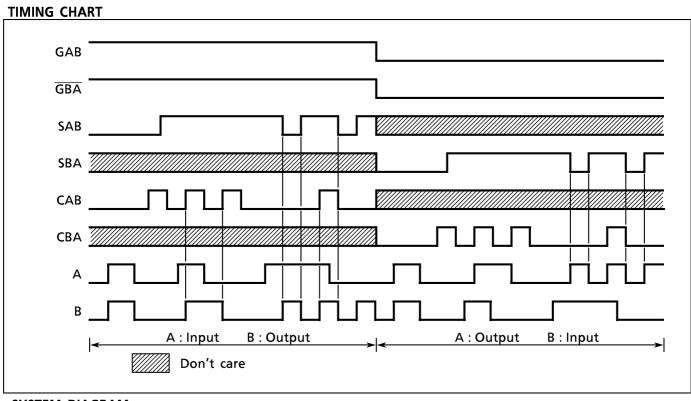
TRUTH TABLE

GAB	GBA	CAB	СВА	SAB	SBA	Α	В	Function
		X*	X*	x	x	INPUTS Z	INPUTS Z	The output functions of A and B Busses are disabled.
L	Н	4		x	X	х	х	Both A and B Busses are used as inputs to the internal flip-flops. Data on the Bus wi be stored on the rising edge of the Clock.
		X*	X *	x	L	OUTPUTS L H	INPUTS L H	The data on the B bus are displayed on the A bus.
L	L	X *		х	L	L H	L H	The data on the B Bus are displayed on th A Bus, and are stored into the B storag flip-flops on the rising edge of CBA.
		X*	X *	х	Н	Qn	Х	The data in the B storage flip-flops ar displayed on the A Bus.
		X *		x	Н	L	L H	The data on the B Bus are stored into the storage flip-flops on the rising edge of CBA and the stored data propagate directly ont the A Bus.
		X*	X*	L	x	INPUTS L H	OUTPUTS L H	The data on the A bus are displayed on th B bus.
			X*	L	x	L	H	The data on the A Bus are displayed on th B Bus, and are stored into the A storag flip-flops on the rising edge of CAB.
Н	H	X *	X*	Н	Х	х	Qn	The data in the A storage flip-flops and displayed on the B Bus.
		<u></u>	X*	Н	×	L	L	The data on the A Bus are stored into the A storage flip-flops on the rising edge of CAB, and the stored data propagate direct onto the B Bus.
Н	L	X *	X *	Н	Н	OUTPUTS Qn	OUTPUTS Qn	The data in the A storage flip-flops are displayed on the B Bus, and the data in th B storage flip-flops are displayed onthe A

Notes: X: Don't CareQn: The data stored into the internal flip-flops by most recent low to high transition of the clock inputs.

Z : High Impedance The clocks are not internally gated with either Output Enable or Select Inputs. Therefore, data on the A and/or B Busses may be clocked into the storage flip-flops at any time.

> 2 2001-05-17



GAB GBA CAB CBA SAB SBA SBA SBA A1 A1 A2 CK Q AB A3 AB CK Q AB A4 AB AB CK AB AB AB AB AB AB AB AB BB

ABSOLUTE MAXIMUM RATINGS

PARAMETER	SYMBOL	VALUE	UNIT
Supply Voltage Range	V_{cc}	− 0.5~7	٧
DC Input Voltage	VIN	$-0.5 \sim V_{CC} + 0.5$	٧
DC Output Voltage	V _{OUT}	$-0.5 \sim V_{CC} + 0.5$	>
Input Diode Current	I _{IK}	± 20	mA
Output Diode Current	I _{OK}	± 20	mA
DC Output Current	I _{OUT}	±35	mA
DC V _{CC} / Ground Current	I _{cc}	± 75	mA
Power Dissipation	P _D	500*	mW
Storage Temperature	T _{stg}	−65~150	°C

*500mW in the range of Ta= $-40^{\circ}\text{C}\sim65^{\circ}\text{C}$. From Ta=65°C to 85°C a derating factor of $-10\text{mW}/^{\circ}\text{C}$ shall be applied until 300mW.

RECOMMENDED OPERATING CONDITIONS

PARAMETER	SYMBOL	VALUE	UNIT
Supply Voltage	V _{cc}	2~6	V
Input Voltage	V _{IN}	0∼V _{cc}	V
Output Voltage	V _{OUT}	0~V _{cc}	V
Operating Temperature	T _{opr}	−40~85	°C
Input Rise and Fall Time	t _r , t _f	$0 \sim 1000 (V_{CC} = 2.0V)$ $0 \sim 500 (V_{CC} = 4.5V)$ $0 \sim 400 (V_{CC} = 6.0V)$	ns

DC ELECTRICAL CHARACTERISTICS

PARAMETER	CVMADOL	TEST CC	V _{cc}	7	a = 25°C		Ta = -40~85°C		UNIT	
PARAIVIETER	SYMBOL	1531 CC	(V)	MIN.	TYP.	MAX.	MIN.	MAX.	ONII	
High - Level Input Voltage	VIH				1.50 3.15 4.20	_ 	_ _ _	1.50 3.15 4.20	_ _ _	>
Low - Level Input Voltage	VIL			2.0 4.5 6.0			0.50 1.35 1.80	=	0.50 1.35 1.80	V
High - Level Output Voltage	V _{OH}	V _{I N} =	$I_{OH} = -20\mu A$	2.0 4.5 6.0	1.9 4.4 5.9	2.0 4.5 6.0	_ _ _	1.9 4.4 5.9	_ _ _	V
Output voitage		V_{IH} or V_{IL}	$I_{OH} = -6 \text{ mA}$ $I_{OH} = -7.8 \text{ mA}$	4.5 6.0	4.18 5.68	4.31 5.80	_	4.13 5.63	_	
Low - Level	V _{OL}	V _{IN} =	$I_{OL} = 20 \mu A$	2.0 4.5 6.0	_ _ _	0.0 0.0 0.0	0.1 0.1 0.1	_ _ _	0.1 0.1 0.1	\ \
Output Voltage	- OL	V _{IH} or V _{IL}	$I_{OL} = 6$ mA $I_{OL} = 7.8$ mA	4.5 6.0	=	0.17 0.18	0.26 0.26	=	0.33 0.33	
3 - State Output Off - State Current	l _{oz}	$V_{IN} = V_{IH} \text{ or } V_{IL}$ $V_{OUT} = V_{CC} \text{ or GND}$		6.0	_	_	± 0.5	_	± 5.0	
Input Leakage Current	I _{IN}	$V_{IN} = V_{CC}$ or GND		6.0	_	_	± 0.1	_	± 1.0	μA
Quiescent Supply Current	I _{CC}	$V_{IN} = V_{C}$	6.0	_	-	4.0	_	40.0		

TIMING REQUIREMENTS (Input $t_r = t_f = 6ns$)

PARAMETER	SYMBOL	TEST CONDITION		Ta=	25°C	Ta = −40~85°C	UNIT
FARAIVIETER	STIVIBOL	TEST CONDITION	V _{CC} (V)	TYP.	LIMIT	LIMIT	UNII
Minimum Pulse Width (CK)	t _{W(L)} t _{W(H)}		2.0 4.5 6.0	_ _ _	75 15 13	95 19 16	
Minimum Set-up Time	t _s		2.0 4.5 6.0		50 10 9	65 13 11	ns
Minimum Hold Time	t _h		2.0 4.5 6.0	= -	5 5 5	5 5 5	
Clock Frequency	f		2.0 4.5 6.0	_ _ _	6 31 36	5 25 29	MHz

AC ELECTRICAL CHARACTERISTICS (Input $t_r = t_f = 6ns$)

	CVMPOL	TEST CONDITION			7	Γa = 25°0	2	Ta = - 4	l0~85°C	UNIT
PARAMETER	SYMBOL	TEST CONDITION	CL (pF)	V _{cc} (V)	MIN.	TYP.	MAX.	MIN.	MAX.	OIVII
Output Transition Time	t _{TLH} t _{THL}		50	2.0 4.5 6.0		25 7 6	60 12 10	_ _ _	75 15 13	
Propagation Delay Time	t _{pLH}		50	2.0 4.5 6.0	_ _ _	74 21 18	150 30 26	_ _ _	190 38 32	
(BUS—BUS)	t _{pHL}		150	2.0 4.5 6.0	_ _ _	91 26 22	190 38 32	_ _ _	240 48 41	
Propagation Delay Time	t _{pLH}		50	2.0 4.5 6.0	_ _ _	98 28 24	210 42 36	_ _ _	265 53 45]
(CAB, CBA — BUS)	t _{pHL}		150	2.0 4.5 6.0	_ _ _	116 33 28	250 50 43	_ _ _	315 63 54	ns
Propagation Delay Time	t _{pLH}		50	2.0 4.5 6.0	_ _ _	81 23 20	170 34 29	_ _ _	215 43 37	
(SAB, SBA — BUS)	t _{pHL}		150	2.0 4.5 6.0	_ _ _	98 28 24	210 42 36	_ _ _	265 53 45	
Propagation Enable Time	t _{pZL}		50	2.0 4.5 6.0	_ _ _	74 21 18	175 35 30	_ _ _	220 44 37	
(GAB, GBA — BUS)	t _{pZH}	$R_L = 1k\Omega$	150	2.0 4.5 6.0	_ _ _	91 26 22	215 43 37		270 54 46	
Output Disable time (GAB, GBA — BUS)	t _{pLZ} t _{pHZ}	$R_L = 1k\Omega$	50	2.0 4.5 6.0	_ _ _	50 21 18	175 35 30	_ _ _	220 44 37	

AC ELECTRICAL CHARACTERISTICS (Input $t_r = t_f = 6ns$) (Cont'd)

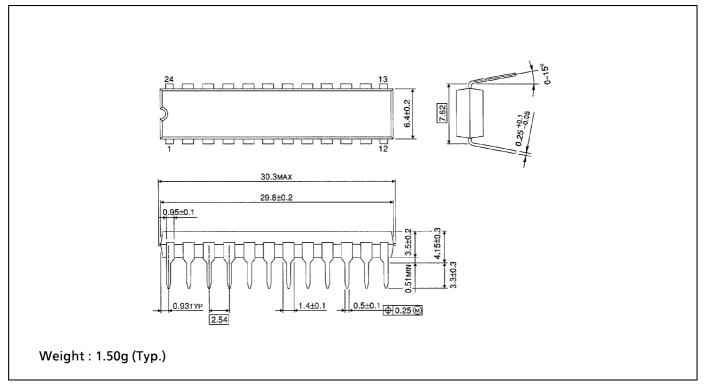
	SYMBOL	TEST CONDITION			7	Ta = 25°0	C	Ta = - 4	LINIT	
PARAMETER	STIVIBOL	TEST CONDITION	(pF)	V _{CC} (V)	MIN.	TYP.	MAX.	MIN.	MAX.	OWIT
Maximum Clock Frequency	f _{MAX}		50	2.0 4.5 6.0	6 31 36	19 67 79	_ _ _	5 25 29		MHz
Input Capacitance	C _{IN}				-	5	10	_	10	
Output Capacitance	C _{OUT}				ı	13	_	_	ı	рF
Power Dissipation Capacitance	C _{PD} (1)				_	39	_	_	_	

Average operating current can be obtained by the equation:

$$I_{CC}$$
 (opr) = $C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC} / 8$ (per bit)

DIP 24PIN PACKAGE DIMENSIONS (DIP24-P-300-2.54)

Unit in mm



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RESTRICTIONS ON PRODUCT USE

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